

DF20L60U**600V 20A****特長**

- SMD
- 低ノイズ
- trr=35ns

Feature

- SMD
- Low Noise
- trr=35ns

用途

- スイッチング電源
- アクティブフィルタ

Main Use

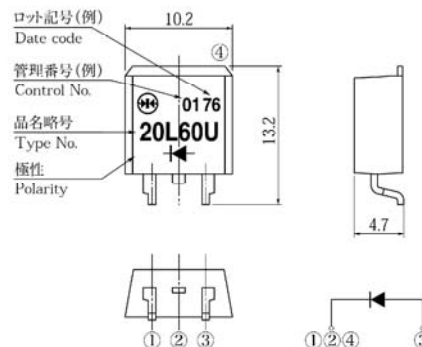
- Switching Regulator
- PFC(Power Factor Correction)

■外観図 OUTLINE

Package : STO-220

Unit:mm

Weight 1.5g (Typ)



外形図については新電元Webサイト又は〈半導体製品一覧表〉をご参照下さい。捺印表示については捺印仕様をご確認下さい。

For details of the outline dimensions, refer to our web site or Semiconductor Short Form Catalog. As for the marking, refer to the specification "Marking, Terminal Connection".

■定格表 RATINGS**●絶対最大定格 Absolute Maximum Ratings** (指定のない場合 $T_c = 25^\circ\text{C}$)

項目 Item	記号 Symbol	条件 Conditions	品名 Type No.	DF20L60U	単位 Unit
保存温度 Storage Temperature	T_{stg}			-55~150	$^\circ\text{C}$
接合部温度 Operation Junction Temperature	T_j			150	$^\circ\text{C}$
せん頭逆電圧 Maximum Reverse Voltage	V_{RM}			600	V
出力電流 Average Rectified Forward Current	I_o	50Hz 正弦波, 抵抗負荷, $T_c = 93^\circ\text{C}$ 50Hz sine wave, Resistance load, $T_c = 93^\circ\text{C}$		20	A
せん頭サージ順電流 Peak Surge Forward Current	I_{FSM}	50Hz 正弦波, 非繰り返し1サイクルせん頭値, $T_j = 25^\circ\text{C}$ 50Hz sine wave, Non-repetitive 1 cycle peak value, $T_j = 25^\circ\text{C}$		160	A

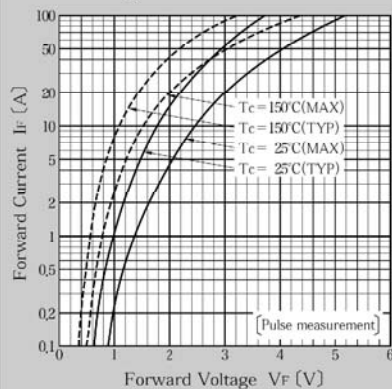
●電氣的・熱的特性 Electrical Characteristics (指定のない場合 $T_c = 25^\circ\text{C}$)

順電圧 Forward Voltage	V_F	$I_F = 20\text{A}$, パルス測定 Pulse measurement	MAX 3.0	V
逆電流 Reverse Current	I_R	$V_R = V_{RM}$, パルス測定 Pulse measurement	MAX 25	μA
逆回復時間 Reverse Recovery Time	trr	$I_F = 0.5\text{A}$, $I_R = 1\text{A}$	MAX 35	ns
接合容量 Junction Capacitance	C_j	$f = 1\text{MHz}$, $V_R = 10\text{V}$	TYP 105	pF
熱抵抗 Thermal Resistance	θ_{jc}	接合部・ケース間 Junction to case	MAX 0.9	$^\circ\text{C/W}$

■特性図 CHARACTERISTIC DIAGRAMS

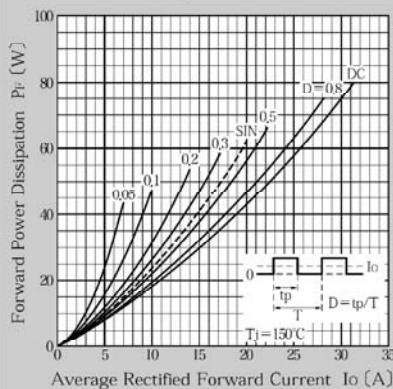
順方向特性

Forward Voltage



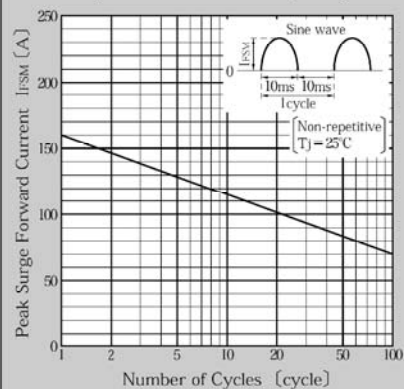
順電力損失曲線

Forward Power Dissipation



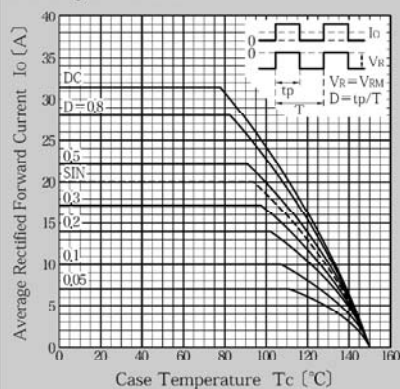
せん頭サージ順電流耐量

Peak Surge Forward Current Capability



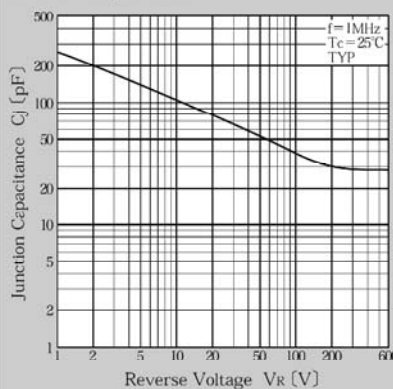
ディレーティングカーブ Tc-Io

Derating Curve Tc-Io



接合容量

Junction Capacitance



- * Sine waveは50Hzで測定しています。
- * 50Hz sine wave is used for measurements.
- * 半導体製品の特性は一般的にバラツキを持っています。
- * Typical is a statistical average of the device's ability.
- * Semiconductor products generally have characteristic variation.
- * Typical is a statistical average of the device's ability.